Special Issue

Microelectronics Reliability

Message from the Guest Editors

The goal of this Special Issue of *Electronics* is to present state-of-the-art investigations on various reliability technologies and cover all levels of integrated systems and manufacturing:

- materials and processes;
- technologies (CMOS, BiCMOS, etc.);
- transistors;
- components (SRAM, DRAM, sensors, power electronics, etc.);
- integrated circuits (processors, controllers, etc.);
- integrated systems (communication, graphic module, etc.); and packages.

Topics of interest on reliability include, but are not limited to:

- traditional reliability topics (TDDB, HCT, EM, etc.);
- life testing;
- accelerated testing;
- maintainability;
- failure mechanisms;
- case studies of physical failures;
- mitigation (proactive and passive);
- reliability models;
- stress mechanisms;
- interconnection issues;
- reliability due to radiation effects;
- telemetry, on-die sensors, and instant health monitoring for fast reliability loops.

Guest Editors

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Deadline for manuscript submissions

closed (30 November 2021)

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About the Journal

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Editor-in-Chief

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Author Benefits

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Journal Rank:

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Rapid Publication:

manuscripts are peer-reviewed and a first decision is provided to authors approximately 16.8 days after submission; acceptance to publication is undertaken in 2.4 days (median values for papers published in this journal in the first half of 2025).